

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|--|-------------------|------------------|---------|------------------|
| S1 | 1 | "20040260502".pn. | US-PGPUB | OR | OFF | 2005/04/28 07:09 |
| S2 | 64 | ((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function) | US-PGPUB | OR | ON | 2005/04/27 14:53 |
| S3 | 33 | ((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function) | USPAT | OR | ON | 2005/04/21 13:43 |
| S4 | 1 | liu.in. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/21 13:58 |
| S5 | 2569 | (hash adj function) | USPAT | OR | ON | 2005/04/21 13:43 |
| S6 | 755 | (hash adj function) and (sha\$1 md5) | USPAT | OR | ON | 2005/04/21 13:43 |
| S7 | 36 | (hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) | USPAT | OR | ON | 2005/04/21 13:56 |
| S8 | 0 | ((ic (integrated adj circuit) semi\$conductor) near3 testing) and (hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) | USPAT | OR | ON | 2005/04/21 13:45 |
| S9 | 0 | (hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (test adj (message communication information data signal) adj (digest summary)) | USPAT | OR | ON | 2005/04/21 13:59 |
| S10 | 1 | (hash adj function) and (sha\$1 md5) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (test adj (message communication information data signal) adj (digest summary)) | US-PGPUB | OR | ON | 2005/04/21 13:57 |
| S11 | 1 | liu.in. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) and (hash adj function) | EPO; JPO; DERWENT | OR | ON | 2005/04/21 13:58 |
| S12 | 129 | (hash adj function) and (sha\$1 md5) and (atm (accelerated adj test adj method) bist (built adj in adj self adj test) (scan adj (test testing))) | USPAT | OR | ON | 2005/04/21 14:00 |

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| S13 | 31 | (hash adj function) and (sha\$1 md5) and (atm (accelerated adj test adj method) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi microprocessor microcomputer) with testing) and (bist (built adj in adj self adj test) (scan adj (test testing))) | USPAT | OR | ON | 2005/04/21 14:07 |
| S14 | 1 | (test adj vector adj data) and (test adj message adj digest) and (hash adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 14:08 |
| S15 | 6649 | (hash adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 14:10 |
| S16 | 9 | (hash adj function) and (test adj (signal data message communication information) adj (digest summary report)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:15 |
| S17 | 2 | (hash adj function) and (test adj (signal data message communication information) adj (digest summary report)) and ((test adj (data signal information)) (test adj vector adj (data signal information))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 14:13 |
| S18 | 1 | (hash adj function) and (test adj (signal data message communication information) adj (digest summary report)) and ((standard adj message) (golden adj signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 14:16 |
| S19 | 4739 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:28 |

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| S20 | 3 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and ((test analysis) adj (message communication data information word sample segment) adj (summary digest report)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:26 |
| S21 | 3 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and ((test analysis) adj (message communication data information word sample segment) adj (summary digest report)) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:28 |
| S22 | 205 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (atm (accelerated adj test adj method)) and ((hash adj function) sha\$1 md5) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:30 |
| S23 | 2 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and ((hash adj function) "sha-1" md5) and (((standard reference) adj (message communication data information word sample segment)) (golden adj signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:30 |
| S24 | 2 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and ((hash adj function) "sha-1" md5) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:30 |

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| S25 | 42 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:32 |
| S26 | 2 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and (hash adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:32 |
| S27 | 2 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and ((accelerated adj test adj method)) and hash | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:32 |
| S28 | 6649 | hash adj function | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:33 |
| S29 | 508 | (hash adj function) and "sha-1" and md5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:34 |
| S30 | 362 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and md5 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:36 |
| S31 | 1 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and md5 and ((accelerated adj test adj (method procedure process methodology routine algorithm program))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:35 |
| S32 | 362 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and "md5" | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:36 |

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| S33 | 9 | (ic (integrated adj circuit) semi\$conductor micro\$processor micro\$computer dsp (digital adj signal adj processor) lsi (large adj scale adj integration) plu plc (programmable adj logic adj (controller unit))) and (hash adj function) and "sha-1" and "md5" and ((standard reference golden) adj (message signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/21 15:36 |
| S34 | 98 | (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) with testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and ((hash "sha-1" md5 sha\$1) adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 09:19 |
| S35 | 2 | (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (testing evaluation analysis)) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) and ((hash "sha-1" md5 sha\$1) adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 07:26 |
| S37 | 2962 | (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 07:56 |
| S38 | 5 | (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((standard reference) adj (message communication) adj (digest report)) (golden adj signature)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:06 |

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|-----|------|--|---|----|----|------------------|
| S39 | 1 | ((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((standard reference) adj (message communication) adj (digest report)) (golden adj signature)) and ((hash transform) adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:06 |
| S40 | 98 | ((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and ((hash transform) adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:07 |
| S41 | 12 | ("6021514" "6125465" "4779273" "6516432" "5574733" "4377757" "5247525" "5412665" "6738939" "20020073373" "20020059547" "20040003330").pn. | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:09 |
| S42 | 0 | ("6021514" "6125465" "4779273" "6516432" "5574733" "4377757" "5247525" "5412665" "6738939" "20020073373" "20020059547" "20040003330").pn. and ((hash sha\$1 md5 transform "sha-1") adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:10 |
| S44 | 1 | (test adj vector adj data) and (test adj message adj digest) and (standard adj message adj digest) and (response adj data) and (hash) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:12 |
| S45 | 2962 | (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:14 |

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|-----|-----|--|---|----|----|------------------|
| S46 | 834 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector)</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:14 |
| S47 | 432 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and (response near3 (data signal information))</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:14 |
| S48 | 4 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and (response near3 (data signal information)) and (test near3 message)</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:17 |
| S49 | 2 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (test near3 vector) and hash and (test near3 message)</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:19 |

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|-----|----|--|---|----|----|------------------|
| S50 | 22 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing))</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:19 |
| S51 | 2 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing)) and (hash "sha-1" sha\$1 md5 shax)</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:20 |
| S52 | 1 | <p>(((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing)) and ((test standard golden protocol prototypical) near3 (message communication vector data information) near3 (digest report summary))</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:23 |
| S53 | 3 | <p>(((accelerated accelerate acceleration autonomous automated automatic self bist (built adj self adj test)) near3 (test testing) near3 (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (test testing)) and ((test standard golden protocol prototypical) near3 (message communication vector data information) near3 (digest report summary))</p> | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:27 |

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|-----|------|--|---|----|-----|------------------|
| S54 | 3 | ((((accelerated accelerate acceleration autonomous automated automatic self bist (built adj self adj test)) near3 (test testing) near3 (method methodology procedure routine algorithm process way step practice))) with (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 (test testing))) and (hash near3 (function module section part component)) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 08:28 |
| S55 | 254 | 324/500.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:52 |
| S56 | 1053 | 324/537.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:42 |
| S57 | 2792 | 324/765.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:42 |
| S58 | 320 | 702/108.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:42 |
| S59 | 97 | 702/109.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:42 |
| S60 | 542 | 702/117.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S61 | 222 | 702/118.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:42 |
| S62 | 202 | 702/120.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S63 | 368 | 714/1.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S64 | 962 | 714/25.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S65 | 1295 | 714/718.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S66 | 514 | 714/719.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S67 | 774 | 714/726.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S68 | 236 | 714/732.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:43 |
| S69 | 8 | 702/117.ccls. and 324/500.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S70 | 11 | 702/117.ccls. and 324/537.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:51 |
| S71 | 36 | 702/117.ccls. and 324/765.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:52 |
| S72 | 28 | 702/117.ccls. and 702/108.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:44 |

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|-----|----|--|-----------------|----|-----|------------------|
| S73 | 2 | 702/117.ccls. and 702/109.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:44 |
| S74 | 45 | 702/117.ccls. and 702/118.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:44 |
| S75 | 35 | 702/117.ccls. and 702/120.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:44 |
| S76 | 0 | 702/117.ccls. and 714/1.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:44 |
| S77 | 10 | 702/117.ccls. and 714/25.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S78 | 15 | 702/117.ccls. and 714/718.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S79 | 3 | 702/117.ccls. and 714/719.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S80 | 9 | 702/117.ccls. and 714/726.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S81 | 5 | 702/117.ccls. and 714/732.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 08:45 |
| S82 | 0 | 702/117.ccls. and 324/500.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:46 |
| S83 | 0 | 702/117.ccls. and 324/537.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:46 |
| S84 | 0 | 702/117.ccls. and 324/765.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:46 |
| S85 | 0 | 702/117.ccls. and 702/108.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:46 |
| S86 | 0 | 702/117.ccls. and 702/109.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S87 | 1 | 702/117.ccls. and 702/118.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:48 |
| S88 | 1 | 702/117.ccls. and 702/120.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:48 |
| S89 | 0 | 702/117.ccls. and 714/1.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S90 | 0 | 702/117.ccls. and 714/25.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S91 | 0 | 702/117.ccls. and 714/718.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |

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| S92 | 0 | 702/117.ccls. and 714/719.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S93 | 0 | 702/117.ccls. and 714/726.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S94 | 1 | 702/117.ccls. and 714/732.ccls. and ((hash sha\$1 md5 "sha-1" transform) near3 function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:47 |
| S95 | 4 | ("5450326" "5991699" "6289292" "6336086").PN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2005/04/25 08:50 |
| S96 | 4 | ("6507800").URPN. | USPAT | OR | OFF | 2005/04/25 08:50 |
| S97 | 6 | 324/500.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:10 |
| S98 | 25 | 324/537.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:09 |
| S99 | 173 | 324/765.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:52 |

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|------|----|---|-----------------|----|----|------------------|
| S100 | 4 | 702/108.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S101 | 0 | 702/109.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S102 | 39 | 702/117.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S103 | 18 | 702/118.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S104 | 20 | 702/120.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |

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|------|------|--|-----------------|----|----|------------------|
| S105 | 98 | "702"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S106 | 390 | "324"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S107 | 39 | "713"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S108 | 1363 | "714"/\$.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:53 |
| S109 | 1 | 714/1.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |

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|------|-----|---|-----------------|----|----|------------------|
| S110 | 19 | 714/25.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |
| S111 | 139 | 714/718.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |
| S112 | 42 | 714/719.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |
| S113 | 324 | 714/726.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |
| S114 | 47 | 714/732.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 08:54 |

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|------|---|---|-----------------|----|----|------------------|
| S115 | 0 | 324/500.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:10 |
| S116 | 0 | 324/537.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:10 |
| S117 | 4 | 324/765.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:12 |
| S118 | 0 | 702/108.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:10 |

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|------|---|---|-----------------|----|----|------------------|
| S119 | 0 | 702/109.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:11 |
| S120 | 5 | 702/117.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:13 |
| S121 | 0 | 702/118.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:11 |
| S122 | 4 | 702/120.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:14 |

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|------|---|--|-----------------|----|----|------------------|
| S123 | 1 | 714/1.ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:12 |
| S124 | 0 | 714/25ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:11 |
| S125 | 0 | 714/718ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:11 |
| S126 | 0 | 714/719ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:11 |

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|------|------|--|---|----|-----|------------------|
| S127 | 0 | 714/726ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:12 |
| S128 | 0 | 714/732ccls. and (((integrated adj circuit) ic semi\$conductor wafer chip lsi (large adj scale adj integration) ((semi\$conductor lsi (large adj scale adj integration)) adj (wafer chip die dice sample specimen)) microprocessor microcomputer) near3 testing) and (((accelerated automated automatic) adj (test testing) adj (method methodology procedure routine algorithm process way step practice)) bist (built adj in adj self adj test) (scan adj (test testing))) and (hash md5 sha\$1 "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/25 09:12 |
| S129 | 114 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/25 09:21 |
| S130 | 601 | 324/763.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:53 |
| S131 | 49 | 324/764.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:52 |
| S132 | 2792 | 324/765.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:52 |
| S133 | 171 | 324/766.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:52 |
| S134 | 309 | 324/767.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:53 |
| S135 | 107 | 324/768.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/25 12:53 |
| S136 | 0 | 324/763.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:06 |
| S137 | 0 | 324/764.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:53 |
| S138 | 0 | 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:53 |

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|------|----|--|-----------------|----|----|------------------|
| S139 | 0 | 324/766.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:53 |
| S140 | 0 | 324/767.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S141 | 0 | 324/768.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S142 | 13 | 702/117.ccls. and 324/763.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S143 | 0 | 702/117.ccls. and 324/764.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S144 | 36 | 702/117.ccls. and 324/765.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:55 |
| S145 | 0 | 702/117.ccls. and 324/766.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S146 | 0 | 702/117.ccls. and 324/767.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S147 | 0 | 702/117.ccls. and 324/768.ccls. | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:54 |
| S148 | 0 | 702/117.ccls. and 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((hash "sha-1" md5) adj function) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:55 |
| S149 | 0 | 702/117.ccls. and 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 12:59 |
| S150 | 0 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:00 |
| S151 | 0 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | USOCR; IBM_TDB | OR | ON | 2005/04/25 13:00 |

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|------|-----|--|-------------------|----|----|------------------|
| S152 | 0 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((transform "sha-1" md5 hash) near3 (output result product)) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | EPO; JPO; DERWENT | OR | ON | 2005/04/25 13:00 |
| S153 | 31 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((compare comparing comparison verify verifying verification) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:03 |
| S154 | 3 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((shorten concatenate concatenation transform) with (response result resultant)) and ((compare comparing comparison verify verifying verification) with ((standard prototype prototypical golden reference) near3 (message signature digest report word))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:05 |
| S155 | 60 | 324/763.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:08 |
| S156 | 1 | 324/764.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:07 |
| S157 | 154 | 324/765.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:13 |
| S158 | 1 | 324/766.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:07 |
| S159 | 2 | 324/767.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:07 |
| S160 | 1 | 324/768.ccls. and ((accelerated adj (test testing)) bist (built adj in adj self adj test)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:07 |
| S161 | 1 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and ((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary))) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:22 |

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|------|---|--|-------------------|----|----|------------------|
| S162 | 0 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and (ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)) | USOCR; IBM_TDB | OR | ON | 2005/04/25 13:21 |
| S163 | 0 | ((accelerated adj (test testing)) bist (built adj in adj self adj test)) and (ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and (hash "sha-1" md5 (transform near3 function)) and ((test testing response result resultant) near3 (data signal information communication message) near3 (digest report summary)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)) | EPO; JPO; DERWENT | OR | ON | 2005/04/25 13:21 |
| S164 | 1 | ((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)) | US-PGPUB; USPAT | OR | ON | 2005/04/25 13:25 |
| S165 | 0 | ((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing))) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)) | USOCR; IBM_TDB | OR | ON | 2005/04/25 13:25 |

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|------|------|---|-------------------|----|-----|------------------|
| S166 | 0 | ((ic (integrated adj circuit) (semiconductor near3 (wafer die dice chip component))) with (accelerated adj (test testing)) and ((test testing input) near3 vector near3 (data signal information communication message)) and ((response result resultant) near3 (data signal information communication message)) and ((standard reference prototype prototypical golden) near3 (data signal information communication message) near3 (digest report summary)) | EPO; JPO; DERWENT | OR | ON | 2005/04/25 13:25 |
| S167 | 1292 | 713/176.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:44 |
| S168 | 143 | 713/179.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:41 |
| S169 | 256 | 713/180.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:41 |
| S170 | 233 | 713/181.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:41 |
| S171 | 998 | 713/193.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:41 |
| S172 | 276 | 713/194.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S173 | 1400 | 714/724.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S174 | 757 | 714/733.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S175 | 350 | 714/734.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S176 | 258 | 714/735.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S177 | 667 | 714/736.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S178 | 80 | 714/737.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:42 |
| S179 | 0 | 702/117.ccls. and 713/176.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S180 | 0 | 702/117.ccls. and 713/179.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S181 | 0 | 702/117.ccls. and 713/180.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S182 | 0 | 702/117.ccls. and 713/181.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S183 | 0 | 702/117.ccls. and 713/193.ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S184 | 0 | 702/117.ccls. and 713/194ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S185 | 0 | 702/117.ccls. and 714/724ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |

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|------|---|---|--------------------|----|-----|------------------|
| S186 | 0 | 702/117.ccls. and 714/733ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S187 | 0 | 702/117.ccls. and 714/734ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:43 |
| S188 | 0 | 702/117.ccls. and 714/735ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:44 |
| S189 | 0 | 702/117.ccls. and 714/736ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:44 |
| S190 | 0 | 702/117.ccls. and 714/737ccls. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 08:44 |
| S191 | 5 | 713/176.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:53 |
| S192 | 3 | 713/176.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:55 |
| S193 | 0 | 713/179.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:55 |
| S194 | 1 | 713/180.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:57 |
| S195 | 1 | 713/181.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |

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|------|---|---|-----------------|----|----|------------------|
| S196 | 1 | 713/193.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S197 | 1 | 713/194.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S198 | 0 | 714/724.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S199 | 0 | 714/733.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S200 | 0 | 714/734.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S201 | 0 | 714/735.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:58 |
| S202 | 0 | 714/736.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:59 |

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|------|-----|--|-------------------|----|----|------------------|
| S203 | 0 | 714/737.ccls. and ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 08:59 |
| S204 | 133 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 09:07 |
| S205 | 122 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 09:07 |
| S206 | 0 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property)) | USOCR; IBM_TDB | OR | ON | 2005/04/27 09:08 |
| S207 | 0 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) and (ip (intellectual adj property)) | EPO; JPO; DERWENT | OR | ON | 2005/04/27 09:08 |
| S208 | 1 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | EPO; JPO; DERWENT | OR | ON | 2005/04/27 09:08 |

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|------|---|--|---|----|----|------------------|
| S209 | 0 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and (hash "sha-1" md5) and ((standard reference gold golden) near3 (message word signature)) | USOCR; IBM_TDB | OR | ON | 2005/04/27 09:28 |
| S210 | 0 | ((accelerated adj (test testing analysis measurement (parametric adj (test measurement)) adj method)) ((scan scanning) adj (test testing measurement)) bist (built adj self adj test) (built\$in\$self\$test)) and ((compare comparing comparison match matching correlate correlating correlation compared matched correlated) with ((hash "sha-1" md5) near3 (result resultant output transform)) with ((standard reference gold golden) near3 (message word signature))) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/27 12:32 |
| S211 | 2 | ("20040664457" "20020138802" "6507800" "6266771" "6757832" "6816968" "6374354" "6708273" "6442525" "6085321" "6795919").pn. and (input (test with vector with (data information))) and (hash "sha-1" md5) and ((test with (communication message) with (digest report)) output) and ((standard reference gold golden) adj (message signature word)) and (limit set\$point threshold (pre\$determined adj requirement)) | US-PGPUB; USPAT | OR | ON | 2005/04/27 10:02 |
| S212 | 1 | (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 12:44 |

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|------|----|---|-------------------|----|----|------------------|
| S213 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | USOCR; IBM_TDB | OR | ON | 2005/04/27 12:50 |
| S214 | 1 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | EPO; JPO; DERWENT | OR | ON | 2005/04/27 12:43 |
| S215 | 16 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 12:47 |
| S216 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | USOCR; IBM_TDB | OR | ON | 2005/04/27 12:47 |

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|------|---|--|--------------------|----|----|------------------|
| S217 | 2 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | DERWENT | OR | ON | 2005/04/27 12:48 |
| S218 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and ((verify verifying verified verification compare compared comparing comparison) with ((standard reference gold golden) near3 (signature message data information digest report))) | EPO; JPO | OR | ON | 2005/04/27 12:47 |
| S219 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) | USOCR; IBM_TDB | OR | ON | 2005/04/27 12:49 |
| S220 | 1 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) | DERWENT | OR | ON | 2005/04/27 12:49 |
| S221 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) | EPO; JPO | OR | ON | 2005/04/27 12:49 |
| S222 | 3 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) | US-PGPUB; USPAT | OR | ON | 2005/04/27 12:49 |

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|------|-------|---|-----------------|----|-----|------------------|
| S223 | 0 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and (((standard reference gold golden) near3 (signature message data information digest report))) | USOCR; IBM_TDB | OR | ON | 2005/04/27 12:50 |
| S224 | 2 | ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash "sha-1" md5) and (((standard reference gold golden) near3 (signature message data information digest report))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:29 |
| S225 | 13208 | liu.in. | US-PGPUB; USPAT | OR | OFF | 2005/04/27 13:28 |
| S226 | 3 | liu.in. and ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:30 |
| S227 | 26 | silverbrook.in. and ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:31 |
| S228 | 1 | silverbrook.in. and ((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash hashing "sha-1" md5) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:34 |

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|------|----|--|-----------------|----|----|------------------|
| S229 | 0 | walmsley.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:32 |
| S230 | 0 | lapstun.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:33 |
| S231 | 0 | sheu.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:33 |
| S232 | 2 | house.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:33 |
| S233 | 1 | siegel.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:34 |
| S234 | 51 | williams.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:34 |

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|------|----|---|---|----|----|------------------|
| S235 | 1 | williams.in. and (((integrated adj circuit) ic semiconductor chip wafer die sample specimen (semiconductor adj (chip wafer die sample specimen))) same (((automatic automated accelerated) near3 (test testing evaluation evaluating) near3 (method methodology process procedure routine program algorithm step)))) and (hash hashing "sha-1" md5) | US-PGPUB; USPAT | OR | ON | 2005/04/27 13:34 |
| S236 | 1 | (((integrated adj circuit) ic semiconductor wafer chip lsi vlsi) near3 testing) and ((hash hashing "sha-1" sha1 md5) adj (function transform)) and shax | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/27 14:56 |
| S237 | 1 | (((integrated adj circuit) ic semiconductor wafer chip lsi vlsi) near3 testing) and shax | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/27 14:56 |
| S238 | 2 | ((hash hashing "sha-1" sha1 md5) adj (function transform)) and shax | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/27 14:58 |
| S239 | 39 | shax | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT ; IBM_TDB | OR | ON | 2005/04/27 14:58 |
| S240 | 3 | (shax (secure adj hash adj algorithm adj accelerator)) | US-PGPUB; USPAT | OR | ON | 2005/04/28 07:10 |
| S241 | 34 | (shax (secure adj hash adj algorithm adj accelerator)) | USOCR; IBM_TDB | OR | ON | 2005/04/28 07:26 |
| S242 | 3 | (shax (secure adj hash adj algorithm adj accelerator)) | EPO; JPO; DERWENT | OR | ON | 2005/04/28 07:10 |
| S243 | 0 | ((ic (integrated adj circuit) wafer chip die semiconductor (semiconductor adj (wafer chip die))) with (test testing analysis calibrating calibration)) and ((shax (secure adj hash adj algorithm adj accelerator))) | USOCR; IBM_TDB | OR | ON | 2005/04/28 07:14 |
| S244 | 0 | ("6507800" "20040133831").pn. and (sha1 md5 shax "sha-1") | US-PGPUB; USPAT | OR | ON | 2005/04/28 07:46 |

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|------|-----|--|------------------------|----|-----|------------------|
| S245 | 126 | (ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit))) | US-PGPUB; USPAT | OR | ON | 2005/04/28 10:25 |
| S246 | 24 | (ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit))) not (print printing camera imager) | US-PGPUB; USPAT | OR | ON | 2005/04/28 11:12 |
| S247 | 6 | ("4987595" "5557346" "5623545" "5631960" "5721777" "5832207").PN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2005/04/28 07:44 |
| S248 | 1 | ("6704871").URPN. | USPAT | OR | OFF | 2005/04/28 07:42 |
| S250 | 1 | (ic (integrated adj circuit) semiconductor wafer chip die (semiconductor adj (wafer chip die))) and ("sha-1" shax md5) and ((accelerated adj (test testing) adj (method procedure methodology process algorithm routine program)) (bist (built adj self adj test)) ((automated automatic) adj (test testing) adj (device equipment apparatus instrument module chip component circuit))) and (shax (secure adj hash adj algorithm adj accelerator)) not (print printing camera imager) | US-PGPUB; USPAT | OR | ON | 2005/04/28 07:43 |
| S251 | 0 | ("6704871").URPN. and ("sha-1" shax md5) and (shax (secure adj hash adj algorithm adj accelerator)) | USPAT | OR | ON | 2005/04/28 07:43 |
| S252 | 0 | ("4987595" "5557346" "5623545" "5631960" "5721777" "5832207").PN. and ("sha-1" shax md5) and (shax (secure adj hash adj algorithm adj accelerator)) | US-PGPUB; USPAT; USOCR | OR | ON | 2005/04/28 07:44 |
| S253 | 1 | "6507800".pn. | USPAT | OR | OFF | 2005/04/28 07:46 |
| S254 | 4 | ("5450326" "5991699" "6289292" "6336086").PN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2005/04/28 07:47 |
| S255 | 4 | ("6507800").URPN. | USPAT | OR | OFF | 2005/04/28 07:49 |
| S256 | 0 | ("5450326" "5991699" "6289292" "6336086").PN. and ("sha-1" shax md5) (shax (secure adj hash adj algorithm adj accelerator)) | US-PGPUB; USPAT; USOCR | OR | ON | 2005/04/28 07:49 |

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|------|----|---|------------------------------|----|-----|------------------|
| S257 | 0 | ("6507800").URPN. and (("sha-1" shax md5) (shax (secure adj hash adj algorithm adj accelerator))) | USPAT | OR | ON | 2005/04/28 07:48 |
| S258 | 0 | ("5450326" "5991699" "6289292" "6336086").PN. and (hash hashing) | US-PGPUB; USPAT; USOCR | OR | ON | 2005/04/28 07:49 |
| S259 | 0 | ("6507800").URPN. and (hash hashing) | USPAT | OR | OFF | 2005/04/28 07:49 |
| S265 | 45 | (hash hashing) and (ip (intellectual adj property)) and (bist (built adj self adj test)) | USPAT | OR | ON | 2005/04/28 08:37 |
| S266 | 3 | (hash hashing) and (ip (intellectual adj property)) and (bist (built adj self adj test)) not (print printer printing camera imager) | USPAT | OR | ON | 2005/04/28 08:37 |

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IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

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((hash <or> sha1 <or> md5) <phrase>
(function <or> transform)) <and> (shax
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